

# **Description**

The SI4936ADY-T1-E3 uses advanced trench technology

to provide excellent RDS(ON), low gate charge and

operation with gate voltages as low as 2.5V. This

device is suitable for use as a

Battery protection or in other Switching application.

#### D2 D1 D1 S2 G2 G1 S1

SOP-8 (SOIC-8)

# **General Features**

 $V_{DS} = 30V I_{D} = 6A$ 

 $R_{DS(ON)} < 30 m\Omega$  @  $V_{GS}=10 V$ 

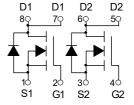
 $R_{DS(ON)} < 42m\Omega$  @  $V_{GS}=4.5V$ 

# **Application**

Battery protection

Load switch

Uninterruptible power supply



**Dual N-Channel MOSFET** 

## **Package Marking and Ordering Information**

Product ID	Pack	Brand	Qty(PCS)
SI4936ADY-T1-E3	SOP-8(SOIC-8)	HXY MOSFET	3000

# Absolute Maximum Ratings@T<sub>j</sub>=25°C(unless otherwise specified)

	<u> </u>	- ,	
Symbol	Parameter	Rating	Units
V <sub>DS</sub>	Drain-Source Voltage	30	V
V <sub>G</sub> S	Gate-Source Voltage	<u>+</u> 20	V
I <sub>D</sub> @T <sub>A</sub> =25°C	Drain Current, V <sub>GS</sub> @ 4.5V <sup>3</sup>	6	А
I <sub>D</sub> @T <sub>A</sub> =70°C	Drain Current, V <sub>GS</sub> @ 4.5V <sup>3</sup>	5	А
Ірм	Pulsed Drain Current <sup>1</sup>	30	А
Pd@Ta=25°C	Total Power Dissipation	2	W
Тѕтс	Storage Temperature Range	-55 to 150	°C
TJ	Operating Junction Temperature Range	-55 to 150	°C
Rthj-a	Maximum Thermal Resistance, Junction- ambient <sup>3</sup>	62.5	°C/W



## Electrical Characteristics (T<sub>J</sub>=25℃ unless otherwise noted)

Symbol	Parameter	Conditions		Min	Тур	Max	Units
STATIC F	STATIC PARAMETERS						
$BV_{DSS}$	Drain-Source Breakdown Voltage	$I_D = -250 \mu A, V_{GS} = 0 V$		30			V
I <sub>DSS</sub> Z	Zero Gate Voltage Drain Current	$V_{DS}$ =30V, $V_{GS}$ =0V				1	μА
			T <sub>J</sub> =55℃			5	μΑ
$I_{GSS}$	Gate-Body leakage current	$V_{DS}$ =0V, $V_{GS}$ =±20V				±100	nA
$V_{GS(th)}$	Gate Threshold Voltage	$V_{DS}=V_{GS}$ $I_{D}=250$ μA		1.2	1.8	2.4	V
$I_{D(ON)}$	On state drain current	$V_{GS}$ =10V, $V_{DS}$ =5V		30			Α
		$V_{GS}$ =10V, $I_D$ =6A			25	30	mΩ
R <sub>DS(ON)</sub>	Static Drain-Source On-Resistance		T <sub>J</sub> =125℃		40	48	11122
		V <sub>GS</sub> =4.5V, I <sub>D</sub> =5A			33	42	mΩ
<b>g</b> <sub>FS</sub>	Forward Transconductance	$V_{DS}$ =5V, $I_{D}$ =6A			15		S
$V_{SD}$	Diode Forward Voltage	I <sub>S</sub> =1A,V <sub>GS</sub> =0V			0.76	1	V
Is	Maximum Body-Diode Continuous Curre	um Body-Diode Continuous Current				2.5	Α
DYNAMIC	PARAMETERS						
C <sub>iss</sub>	Input Capacitance				255	310	рF
C <sub>oss</sub>	Output Capacitance	V <sub>GS</sub> =0V, V <sub>DS</sub> =15V, f=1MHz			45		pF
C <sub>rss</sub>	Reverse Transfer Capacitance				35	50	pF
$R_g$	Gate resistance	V <sub>GS</sub> =0V, V <sub>DS</sub> =0V, f=1MHz		1.6	3.25	4.9	Ω
SWITCHI	SWITCHING PARAMETERS						
Q <sub>g(10V)</sub>	Total Gate Charge	V <sub>GS</sub> =10V, V <sub>DS</sub> =15V, I <sub>D</sub> =6A			5.2	6.3	nC
Qg <sub>(4.5V)</sub>					2.55	3.2	nC
$Q_{gs}$	Gate Source Charge				0.85		nC
$Q_{gd}$	Gate Drain Charge				1.3		nC
t <sub>D(on)</sub>	Turn-On DelayTime				4.5		ns
t <sub>r</sub>	Turn-On Rise Time	$V_{GS}$ =10V, $V_{DS}$ =15V, $R_L$ =2.5 $\Omega$ , $R_{GEN}$ =3 $\Omega$			2.5		ns
t <sub>D(off)</sub>	Turn-Off DelayTime				14.5		ns
t <sub>f</sub>	Turn-Off Fall Time				3.5		ns
t <sub>rr</sub>	Body Diode Reverse Recovery Time	I <sub>F</sub> =6A, dI/dt=100A/μs			8.5		ns
Q <sub>rr</sub>	Body Diode Reverse Recovery Charge	I <sub>F</sub> =6A, dI/dt=100A/μs			2.2		nC

A. The value of  $R_{\theta JA}$  is measured with the device mounted on  $1\text{in}^2$  FR-4 board with 2oz. Copper, in a still air environment with  $T_A$  =25°C. The value in any given application depends on the user's specific board design.

B. The power dissipation  $P_D$  is based on  $T_{J(MAX)}$ =150°C, using  $\leqslant$  10s junction-to-ambient thermal resistance.

C. Repetitive rating, pulse width limited by junction temperature  $T_{J(MAX)}$ =150°C. Ratings are based on low frequency and duty cycles to keep initial  $T_J$ =25°C.

D. The  $R_{\theta JA}$  is the sum of the thermal impedence from junction to lead  $R_{\theta JL}$  and lead to ambient.

E. The static characteristics in Figures 1 to 6 are obtained using <300 $\mu$ s pulses, duty cycle 0.5% max.

F. These curves are based on the junction-to-ambient thermal impedence which is measured with the device mounted on  $1\text{in}^2$  FR-4 board with 2oz. Copper, assuming a maximum junction temperature of  $T_{J(MAX)}=150$ °C. The SOA curve provides a single pulse ratin g.



### TYPICAL ELECTRICAL AND THERMAL CHARACTERISTICS

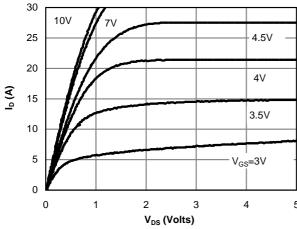


Fig 1: On-Region Characteristics (Note E)

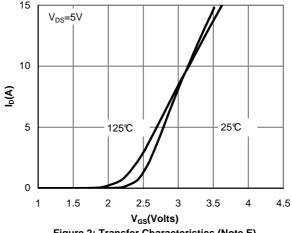


Figure 2: Transfer Characteristics (Note E)

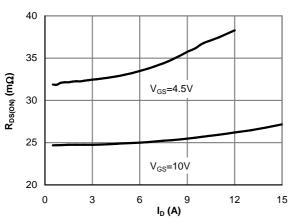


Figure 3: On-Resistance vs. Drain Current and Gate Voltage (Note E)

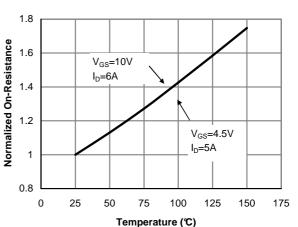


Figure 4: On-Resistance vs. Junction Temperature (Note E)

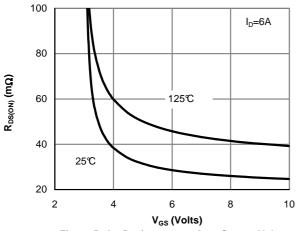


Figure 5: On-Resistance vs. Gate-Source Voltage (Note E)

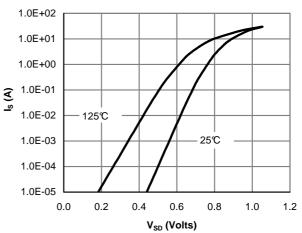
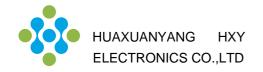
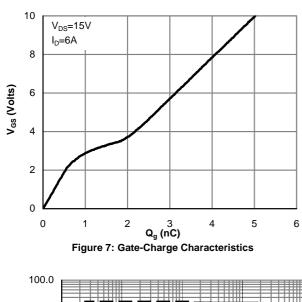
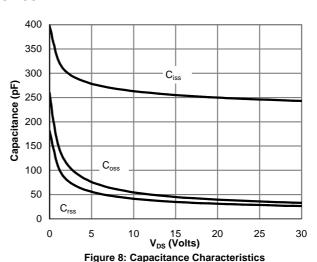


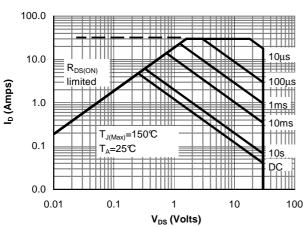
Figure 6: Body-Diode Characteristics (Note E)



### TYPICAL ELECTRICAL AND THERMAL CHARACTERISTICS







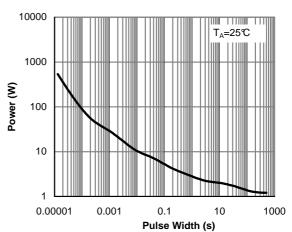


Figure 10: Maximum Forward Biased Safe Operating Area (Note F)

Figure 11: Single Pulse Power Rating Junction-to-Ambient (Note F)

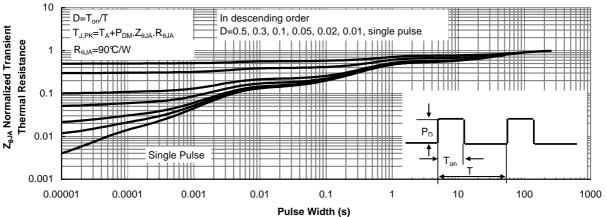
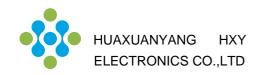
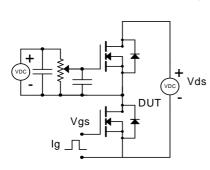
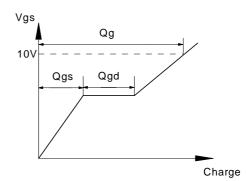


Figure 12: Normalized Maximum Transient Thermal Impedance (Note F)

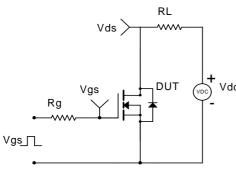


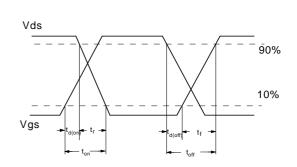
## Gate Charge Test Circuit & Waveform



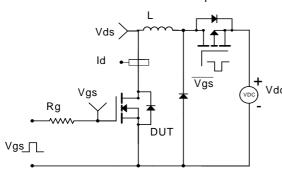


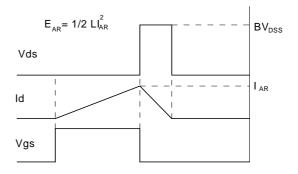
Resistive Switching Test Circuit & Waveforms



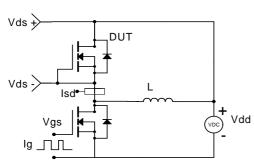


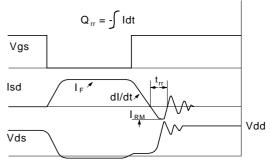
Unclamped Inductive Switching (UIS) Test Circuit & Waveforms

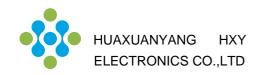




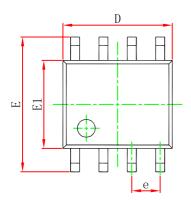
## Diode Recovery Test Circuit & Waveforms

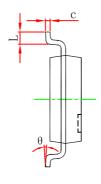


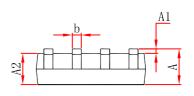




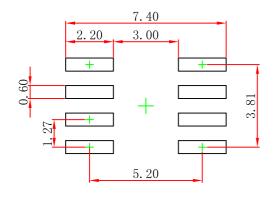
# **SOP-8(SOIC-8) Package Outline Dimensions**







Symbol	Dimensions In Millimeters		Dimensions In Inches		
	Min	Max	Min	Max	
A	1. 350	1.750	0.053	0.069	
A1	0.100	0.250	0.004	0.010	
A2	1.350	1.550	0.053	0.061	
b	0.330	0.510	0.013	0. 020	
c	0.170	0.250	0.007	0.010	
D	4.800	5.000	0.189	0. 197	
e	1.270 (BSC)		0.050 (BSC)		
E	5.800	6.200	0. 228	0.244	
E1	3.800	4.000	0.150	0.157	
L	0.400	1.270	0.016	0.050	
θ	0°	8°	0°	8°	



- Note: 1.Controlling dimension:in millimeters.
- 2.General tolerance:± 0.05mm.
  3.The pad layout is for reference purposes only.



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